Phase transition of ZnF₂ under high pressure and high temperature

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Introduction

Numerous MX_2 -type chemical materials with the rutile-type structure ($P4_{/mnm}$) have been investigated about their high-pressure behavior since synthesis of rutile type SiO₂. High-pressure behavior of ZnF₂ was not clear from the viewpoint of crystallography; however it also has the rutile-type structure at ambient condition, as shown in Fig. 1-a). Recently, a pressure-induced transition to the CaCl₂-type structure has been observed at 4.5 GPa by a Raman study, and the PdF₂-type structure has been predicted to be stable as a high-pressure phase in the pressure condition higher than 6.5 GPa by a theoretical study.

The aim of the present study is to observe highpressure and high-temperature behavior of ZnF_2 by highresolution X-ray diffraction method, and to compare the experimental result with those of the Raman study and the theoretical study.

Experimental

X-ray diffraction patterns were collected by an energydispersive type method using a large volume cubic press apparatus "MAX80" at PF-AR-NE5C. The detail of highpressure and high-temperature experiments was described in our article [1].

Result and discussion

X-ray diffraction patterns of ZnF_2 were broadening by increasing pressure under solid state compression at room temperature. The diffraction pattern became as sharp as that of the starting materials by elevating temperature. All observed diffraction lines at 5.43 GPa and 400 °C could be indexed on an orthorhombic cell of the CaCl₂-type structure (*Pnnm*, Z = 2), as shown in Fig. 1-b). It was consistent with two previous studies about the rutile-CaCl₂ type transition in ZnF₂: the critical pressure value was determined to be 4.5 GPa by the Raman study and to be 4 GPa by the electrical structure calculating study.

Another high-pressure phase observed at 15.3 GPa and 350°C, and all diffraction lines could be indexed on a cubic cell, as shown in Fig. 1-c). The selection rule of the cubic phase (0kl; k = 2n and h00; h = 2n) demonstrated that the high-pressure phase had the PdF₂-type structure (*Pa-3*, Z = 4).

The PdF_2 -type phase remained at room temperature after a cooling process under the high-pressure condition, and the single phase was observed above 4 GPa in a pressure-release process at room temperature. The bulk modulus and initial volume of the PdF_2 -type phase were determined to be $K_0 = 115 \pm 2$ GPa and $V_0 / Z = 31.99 \pm 0.02$ Å³, respectively. These two values were in good agreement with the calculation ($K_0 = 116$ GPa and $V_0 = 32.38$ Å³). The determined initial volume of the PdF₂-type phase is 8.1 % smaller than that of the rutile-type phase. The X-ray diffraction pattern at ambient condition demonstrated that the PdF₂-type phase completely reverted to a mixture of the rutile-type phase and the α -PbO₂ type phase, as shown in Fig. 1-d).



Fig. 1 Typical energy-dispersive type X-ray diffraction patterns of ZnF_2 , taken at $2\theta = 4.5^{\circ}$; a) the rutile-type phase, b) the CaCl₂-type phase, c) the PdF₂-type phase and d) a mixture of the rutile-type phase (r) and the α -PbO, type phase (α).

Reference

[1] K. Kusaba et al., Solid State Commun., **145**, 279 (2008).

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